

# CERTIFICATE OF ANALYSIS

**ERM<sup>®</sup>-EB377****CuSn6**

## Certified Values

	Certified value <sup>1)</sup>	Uncertainty <sup>2)</sup>
Element	Mass fraction in %	
Cu	94.04	± 0.05
Sn	5.92	± 0.13
Element	Mass fraction in mg/kg	
Ag	64.4	± 1.1
Al	45.1	± 1.2
Bi	42.2	± 1.5
Cr	66.9	± 2.1
Fe	104.2	± 2.7
Mn	92.1	± 2.1
Ni	107.4	± 1.5
Pb	44.9	± 2.3
Sb	13.0	± 1.3
Se	55	± 4
Zn	100.6	± 3.0

<sup>1)</sup> Unweighted mean value of the means of accepted sets of data (at least 5 usually 6), each set being obtained in a different laboratory and/or a different method of measurement. The values are traceable to the SI (Système International d'Unités) via calibration using sufficiently pure substances of known stoichiometry.

<sup>2)</sup> Estimated expanded uncertainty *U* with a coverage factor of about *k*=2, corresponding to a level of confidence of 95 %, as defined in the Guide to the expression of uncertainty in measurement, ISO, 1993. For Sn inhomogeneity contributed significantly to the uncertainty.

This certificate is valid until 09/2053; this validity may be extended as further evidence of stability becomes available.

The minimum sample size for wet chemical analysis is 0.5 g.

## NOTE

European Reference Material ERM®-EB377 was originally certified as BAM-377. It was produced and certified under the responsibility of Bundesanstalt für Materialforschung und –prüfung (BAM) in cooperation with the Committee of Chemists of the GDMB, Gesellschaft für Bergbau, Metallurgie, Rohstoff- und Umwelttechnik according to the principles laid down in the technical guidelines of the European Reference Materials® co-operation agreement between BAM-LGC-IRMM. Information on these guidelines is available on the Internet (<http://www.erm-crm.org>).

Accepted as an ERM®, Berlin, 2004-04-14.

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## Indicative Values<sup>3)</sup>

	Indicative value <sup>4)</sup>	Uncertainty <sup>5)</sup>
Element	Mass fraction in mg/kg	
S	6.8	± 0.8
Element	Mass fraction in mg/kg	
Cd, Mg, Te, Ti	< 1	
Co	< 2	
As, P	< 10	
Si	134	

<sup>3)</sup> Values were not certified, but given as indicative values, when the number of accepted data sets was considered to be too low, when the spread from the round robin certification was considerably larger than the state of the practice or when only 'lower as' values were reported from the round robin certification.

<sup>4)</sup> Unweighted mean value of the means of accepted sets of data, each set being obtained in a different laboratory and/or a different method of measurement. The values are traceable to the SI (Système International d'Unités) via calibration using sufficiently pure substances of known stoichiometry.

<sup>5)</sup> Estimated expanded uncertainty  $U$  with a coverage factor of about  $k=2$ , corresponding to a level of confidence of 95 %, as defined in the Guide to the expression of uncertainty in measurement, ISO, 1993.

**MEANS OF ACCEPTED DATA SETS (FOR ONE METHOD AT ONE LABORATORY, RESPECTIVELY)**

Mass fraction in %

Line No..	Cu	Sn
1	93.94	5.84
2	93.98	5.85
3	94.01	5.87
4	94.06	5.89
5	94.07	5.90
6	94.09	5.91
7	94.09	5.92
8	94.10	5.93
9	94.14	5.98
10		5.99
11		6.01
12		
13		
14		
15		
16		
<i>M</i> :	94.04	5.92
<i>s<sub>M</sub></i> :	0.06	0.06
<i>S̄<sub>i</sub></i> :	0.04	0.05

Mass fraction in mg/kg

Ag	Al	Bi	Cr	Fe	Mn	Ni	Pb	Sb	Se	Zn	
61.7	43.4	-	-	-	-	-	39.8	10.8	-	90.1	
63.3	44.4	41.0	60.0	98	87.4	104.3	41.0	11.7	48.5	93.0	
63.7	44.9	41.4	62.2	98	88.3	104.4	44.5	12.0	50.2	95.1	
64.3	45.0	41.5	62.3	100	89.4	105.8	44.9	12.9	52.4	96.7	
64.6	46.0	41.5	64.9	102	90.1	106.5	45.4	13.0	55.8	97.9	
64.9	46.3	43.5	65.0	102	90.2	106.6	46.4	14.1	55.9	98.3	
65.4	-	44.4	66.0	105	90.5	106.8	46.7	14.7	58.2	100.4	
65.7			66.6	106	91.1	106.9	47.8	14.9	58.5	100.6	
65.8			67.4	107	91.2	106.9	48.1		58.8	100.6	
-			68.0	107	92.8	107.3	-			103.7	
			68.3	108	95.4	108.0				104.3	
			68.6	108	96.2	108.2				105.8	
			68.6	111	97.2	110.8				106.3	
			70.3		97.3	113.6				106.7	
			72.2			-				109.0	
			73.1								
<i>M</i> :	64.4	45.0	42.2	66.9	104	92.1	107.4	44.9	13.0	55	101
<i>s<sub>M</sub></i> :	1.3	1.1	1.4	3.7	4	3.4	2.5	2.9	1.5	4	6
<i>S̄<sub>i</sub></i> :	0.9	1.6	1.2	1.2	2.2	1.6	1.7	1.0	0.7	1.6	2.1

The laboratory mean values have been examined statistically to eliminate outlying values. Where a " - " appears in the table it indicates that an outlying value has been omitted. A data set consists of at least 5 but usually 6 single values of one laboratory. "<"-values have not been considered in statistical evaluation.

*M* : mean of means of data sets

*S̄<sub>i</sub>* : mean of standard deviations of data sets under repeatability conditions

*s<sub>M</sub>* : standard deviation of means of data sets

 numbers in *italics* are indicative values

### Mass fraction in mg/kg (indicative values)

Line No.	As	Cd	Co	Mg	P	S	Si	Te	Ti
1	1	< 1	0.14	0.7	5	6.5	121	0.6	0.3
2	< 1	< 1	0.3	0.7	< 2	6.5	147	< 0.5	< 1
3	< 3	< 1	2.0	< 0.3	< 10	6.7		< 1	< 1
4	< 3	< 1	< 1	< 1	< 10	7.5			
5	< 10	< 1	< 1	< 2	< 10	< 5			
6	< 10	< 1	< 1	< 5					
7		< 1.5	< 1.5						
8			< 5						
9									
10									

### ANALYTICAL METHOD USED FOR CERTIFICATION

Element	Line no.	Method
Cu	1	X-ray fluorescence analysis
	2, 7, 9	Electrogravimetry, separation of Sn
	3, 4, 5, 6, 8	Electrogravimetry
Sn	1, 2	Iodometric titration
	3, 5, 6, 9, 10	ICP OES
	4, 8	FAAS
	7	X-ray fluorescence analysis
	11	PAA
Ag	1, 2	ICP OES
	3	PAA
	4	NAA
	5	IDMS
	6, 8, 9	FAAS
	7	FAAS, separation of Sn
	10	ICP OES, separation of Sn, electrolytic separation of Cu
Al	1, 2, 4, 5	ICP OES
	3, 6	ICP OES, separation of Sn, electrolytic separation of Cu
	7	Photometric with Chromazurol S
Bi	1	FAAS, separation of Sn, La(OH) <sub>3</sub> -precipitation
	2	FAAS, electrolytic separation of Cu
	3	ICP OES
	4, 7	FAAS
	5, 6	ET AAS

Cr	1, 4 2, 5 3, 10, 13, 16 6 7, 9, 11, 14, 15 8 12	FAAS, separation of Sn, electrolytic separation of Cu FAAS ICP OES, separation of Sn, electrolytic separation of Cu PAA ICP OES NAA IDMS ICP OES
Fe	1, 3, 4, 8, 10 2, 12 5 6 7 9, 11 13	ICP OES, separation of Sn, electrolytic separation of Cu FAAS, separation of Sn, La(OH) <sub>3</sub> -precipitation FAAS, electrolytic separation of Cu FAAS, separation of Sn, electrolytic separation of Cu FAAS IDMS
Mn	1, 13 2, 11, 14 3 4, 6, 8, 10, 12 5, 7 9	FAAS, separation of Sn, electrolytic separation of Cu ICP OES, separation of Sn, electrolytic separation of Cu FAAS, electrolytic separation of Cu ICP OES FAAS PAA
Ni	1, 3, 13 2, 4, 8, 9, 10 5 6, 15 7, 12 11 14	ICP OES, separation of Sn, electrolytic separation of Cu ICP OES FAAS, electrolytic separation of Cu FAAS, separation of Sn, electrolytic separation of Cu FAAS IDMS PAA
Pb	1 2 3, 5, 9 4, 7, 8 6 10 11	FAAS, separation of Sn, La(OH) <sub>3</sub> -precipitation FAAS, electrolytic separation of Cu FAAS ICP OES IDMS FAAS, separation of Sn, electrolytic separation of Cu ICP OES, separation of Sn, electrolytic separation of Cu
Sb	1 2 3 4 5 6 7 8	ET AAS FAAS, electrolytic separation of Cu ET AAS, La(OH) <sub>3</sub> -precipitation PAA NAA Photometric with Rhodamine B FAAS ICP OES
Se	1 2 3 4 5, 6, 8, 9 7	Photometrie PAA FAAS, electrolytic separation of Cu NAA ICP OES ET AAS

Zn	1 2, 4, 5 3, 8, 9, 15 6 7 10 11, 12, 13 14	NAA ICP OES FAAS, ICP OES, electrolytic separation of Cu IDMS FAAS, separation of Sn, electrolytic separation of Cu ICP OES, separation of Sn, electrolytic separation of Cu FAAS, electrolytic separation of Cu
As	1 2 3 4 5 6	ET AAS, with Se as collector precipitate FAAS, electrolytic separation of Cu PAA NAA ICP OES, separation of Sn, electrolytic separation of Cu ICP OES
Cd	1, 2, 3, 7 4, 5 6	ICP OES ICP OES, separation of Sn, electrolytic separation of Cu FAAS, electrolytic separation of Cu
Co	1 2, 3, 4, 7 5 6, 8	NAA ICP OES FAAS, electrolytic separation of Cu ICP OES, separation of Sn, electrolytic separation of Cu
Mg	1, 2, 3 4 5, 6	ICP OES FAAS, electrolytic separation of Cu ICP OES, separation of Sn, electrolytic separation of Cu
P	1, 3, 4 2, 5	ICP OES Photometric as phosphovanadomolybdate
S	1 2 3 4 5	Photometric determination of H <sub>2</sub> S as Molybdenum Blue ICP OES Microtitration of sulphide Coulometry after combustion Infrared absorption after combustion
Si	1, 2	ICP OES
Te	1 2 3	ET AAS, with Se as collector precipitate ET AAS FAAS, electrolytic separation of Cu
Ti	1, 2, 3	ICP OES

**Abbreviations:**

- ET AAS: Electrothermal Atomic Absorption Spectrometry  
 FAAS: Flame Atomic Absorption Spectrometry  
 ICP-MS: Inductively Coupled Plasma - Mass Spectrometry  
 ICP OES: Inductively Coupled Plasma - Optical Emission Spectrometry  
 IDMS: Isotope Dilution Mass Spectrometry  
 NAA: Neutron Activation Analysis  
 PAA: Photon Activation Analysis

## DESCRIPTION OF THE SAMPLE

The Reference Material is available in the form of discs (40 mm diameter and 30 mm height). It is intended for establishing and checking the calibration of optical emission and X-ray spectrometers for the analysis of samples of similar materials

## PARTICIPANTS

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## INSTRUCTIONS FOR USE

Before use, the surface of the material must be cleaned by turning on a lathe.

## STORAGE

The material should be stored at ambient conditions in a dry and clean environment.

## TECHNICAL REPORT

A detailed technical report (in German) describing the analysis procedures and the treatment of the analytical data used to certify ERM®-EB377 is available on request.

Supply of Reference Materials by Bundesanstalt für Materialforschung und –prüfung:

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